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Journal Papers

1. K. S. Li, X. J. Leon, L. Y Chen, S. J. Wang, Y. A. Huang, J. E. Chen, H. C. Liang, and *C. L. Hsu, "Wafer Defect Pattern Labeling and Recognition Using Semi-supervised Learning," *IEEE Transaction on Semiconductor Manufacturing (TSM),* vol. 35, issue. 2, pp. 291-299, May. 2022. (SCI).
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4. K. C.-C. Cheng, L. L.-Y Chen, J.-W. Li, K. S.-M. Li, N.C.-Y, Tsai, S.-J. Wang, A.Y.-A. Huang, L. Chou, C.-S. Lee, J.E. Chen, H.-C. Liang, and *C.-L. Hsu, "Machine Learning Based Detection Method for Wafer Test Induced Defects," *IEEE Transactions on Semiconductor Manufacturing (TSM),* vol. 34, issue. 2, pp. 161-167, May. 2021. (SCI)
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Book Chapter

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